

Modified Form PTO/SB/08A

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		<i>Complete If Known</i>	
		Application Number	10/034,528
		First Named Inventor	Eldridge et al.
		Filing Date	December 27, 2001
		Group Art Unit	2829
		Examiner Name	Paresh H. Patel
No. of Sheets: 9	No. of Refs.: 309	Attorney Docket No.	P6C3-US

U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No. 1	U.S. Patent Document		Name of Patentee or Applicant	Publication Date	Related	Copy Enclosed
		Number	Kind Code ²				
	1	3,217,283		Shlesinger, Jr.	11/1/1965		No
	2	3,509,270		Dube et al.	4/28/1970		No
	3	3,616,532		Beck	11/2/1971		No
	4	3,795,037		Luttmer et al.	3/5/1974		No
	5	3,806,801		Bove	4/23/1974		No
	6	3,826,984 (Previously Submitted 7/10/02)		Epple	4/30/1974		No
	7	3,866,119		Ardezzone et al.	2/11/1975		No
	8	3,911,361		Bove et al.	10/7/1975		No
	9	3,941,916		Morse	3/2/1976		No
	10	3,963,986 (Previously Submitted 5/25/04)		Morton et al.	6/15/1976		No
	11	4,027,935		Byrnes et al.	6/7/1977		No
	12	4,195,259		Reid et al.	3/25/1980		No
	13	4,251,772		Worsham et al.	2/17/1981		No
	14	4,295,700		Sado	10/20/1981		No
	15	4,312,117		Robillard et al.	1/26/1982		No
	16	4,358,326		Doo	11/9/1982		No
	17	4,396,935		Schuck	8/2/1983		No
	18	4,423,376		Brynes et al.	12/27/1983		No
	19	4,465,990		Gibson	8/14/1984		No
	20	4,506,215		Coughlin	3/19/1985		No
	21	4,563,640		Hasegawa	1/7/1986		No
	22	4,566,184		Higgins	1/28/1986		No
	23	4,567,433 (Previously Submitted 7/10/02)		Ohkubo et al.	1/28/1986		No
	24	4,593,243		Lao et al.	6/3/1986		No
	25	4,599,559		Evans	7/8/1986		No
	26	4,606,931		Olsen et a.	8/19/1986		No
	27	4,626,066		Levinson	12/2/1986		No
	28	4,667,219		Lee et al.	5/19/1987		No
	29	4,674,180		Zavracky et al.	6/23/1987		No
	30	4,719,417		Evans	1/12/1988		No
	31	4,752,590		Adams et al.	6/21/1988		No
	32	4,764,848		Simpson	8/16/1988		No
	33	4,774,462		Black	9/27/1988		No
	34	4,784,972		Hatada et al.	11/15/1988		No
	35	4,793,814		Zifcak et al.	12/27/1988		No

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. 1	U.S. Patent Document	Name of Patentee or Applicant	Publication Date	Related	Copy Enclosed
		Number Kind Code ²				
	36	4,795,977 (Previously Submitted 11/25/02)	Frost et al.	1/3/1989		No
	37	4,816,754	Buechele et al.	3/28/1989		No
	38	4,837,622	Whann et al.	6/6/1989		No
	39	4,864,227	Sato	9/5/1989		No
	40	4,875,614	Cipolla et al.	10/24/1989		No
	41	4,885,126	Polonio	12/5/1989		No
	42	4,892,122	Ickes	1/9/1990		No
	43	4,897,598	Doemens et al.	1/30/1990		No
	44	4,899,099	Mendenhall et al.	2/6/1990		No
	45	4,900,695	Takahashi et al.	2/13/1990		No
	46	4,901,013	Benedetto et al.	2/13/1990		No
	47	4,906,920	Huff et al.	3/6/1990		No
	48	4,912,822	Zdebllick et al.	4/3/1990		No
	49	4,916,002	Carver	4/10/1990		No
	50	4,918,032	Jain et al.	4/17/1990		No
	51	4,920,639	Yee	5/1/1990		No
	52	4,928,061	Dampier et al.	5/22/1990		No
	53	4,931,726	Kasukabe et al.	6/5/1990		No
	54	4,935,694	Clarridge	6/19/1990		No
	55	4,959,515	Zavracky et al.	9/25/1990		No
	56	4,961,052	Tada et al.	10/2/1990		No
	57	4,961,709	Noschese	10/9/1990		No
	58	4,963,822	Prokopp	10/16/1990		No
	59	4,975,638	Evans et al.	12/4/1990		No
	60	4,987,781	Reimann	1/29/1991		No
	61	4,989,069	Hawkins	1/29/1991		No
	62	4,995,941	Nelson et al.	2/26/1991		No
	63	4,998,885	Beaman	3/12/1991		No
	64	5,012,187 (Previously Submitted 1/26/05)	Littlebury et al.	4/30/1991		No
	65	5,042,148	Tada et al.	8/27/1991		No
	66	5,055,777	Bonelli et al.	8/10/1991		No
	67	5,056,783	Matcovich et al.	10/15/1991		No
	68	5,061,192	Chapin et al.	10/29/1991		No
	69	5,086,337	Noro et al.	2/4/1992		No
	70	5,092,172	Overman et al.	3/3/1992		No
	71	5,095,401	Zavracky et al.	3/10/1992		No
	72	5,098,305	Krajewski et al.	3/24/1992		No
	73	5,098,860	Chakravorty et al.	3/24/1992		No
	74	5,103,557 (Previously Submitted 7/10/02)	Leedy	4/14/1992		No
	75	5,113,764	Mandigo et al.	5/19/1992		No
	76	5,124,639	Carlin et al.	6/23/1992		No
	77	5,127,837	Shah et al.	7/7/1992		No
	78	5,130,276	Adams et al.	7/14/1992		No
	79	5,132,613	Papae et al.	7/21/1992		No

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	U.S. Patent Document	Name of Patentee or Applicant	Publication Date	Related	Copy Enclosed
		Number Kind Code ²				
	80	5,148,103 (Previously Submitted 7/10/02)	Pasiecznik, Jr.	9/15/1992		No
	81	5,151,651	Shibata et al.	9/29/1992		No
	82	5,171,713	Matthews et al.	12/15/1992		No
	83	5,171,992	Clabes et al.	12/15/1992		No
	84	5,172,050	Swapp	12/15/1992		No
	85	5,172,053	Itoyama	12/15/1992		No
	86	5,175,496	Collins et al.	12/29/1992		No
	87	5,177,661	Zavracky et al.	1/15/1993		No
	88	5,189,323	Carr et al.	2/23/1993		No
	89	5,189,777	Guckel et al.	3/2/1993		No
	90	5,206,983	Guckel et al.	5/4/1993		No
	91	5,210,485	Kreiger et al.	5/11/1993		No
	92	5,214,657	Farnworth et al.	5/25/1993		No
	93	5,221,415	Albrecht et al.	6/22/1993		No
	94	5,225,037	Elder et al.	7/6/1993		No
	95	5,225,777	Bross et al.	7/6/1993		No
	96	5,247,250	Rios	9/21/1993		No
	97	5,260,926	Kuroda et al.	11/9/1993		No
	98	5,262,000	Welbourn et al.	11/16/1993		No
	99	5,280,236	Takahashi et al.	1/18/1994		No
	100	5,294,039	Pai et al.	3/15/1994		No
	101	5,308,440	Chino et al.	5/3/1994		No
	102	5,308,443	Sugihara	5/3/1994		No
	103	5,309,324	Herandez et al.	5/3/1994		No
	104	5,313,157	Pasiecznik	5/17/1994		No
	105	5,321,453	Mori et al.	6/14/1994		No
	106	5,331,275	Ozaki et al.	7/19/1994		No
	107	5,338,975	Cole et al.	8/16/1994		No
	108	5,343,366	Cipolla et al.	8/30/1994		No
	109	5,353,498	Fillion et al.	10/11/1994		No
	110	5,354,205	Feigenbaum et al.	10/11/1994		No
	111	5,355,079	Evans et al.	10/11/1994		No
	112	5,364,742	Fan et al.	11/15/1994		No
	113	5,367,165	Toda et al.	11/22/1994		No
	114	5,367,584	Ghezze et al.	11/22/1994		No
	115	5,367,585	Ghezze et al.	11/22/1994		No
	116	5,371,431	Jones et al.	12/6/1994		No
	117	5,371,654	Beaman et al.	12/6/1994		No
	118	5,374,792	Ghezze et al.	12/20/1994		No
	119	5,386,110	Toda et al.	1/31/1995		No
	120	5,386,341	Olson et al.	1/31/1995		No
	121	5,395,253 (Previously Submitted 7/10/02)	Crumly	3/7/1995		No
	122	5,396,066	Ikeda et al.	3/7/1995		No
	123	5,399,232	Albrecht et al.	3/21/1995		No
	124	5,399,415	Chen et al.	3/21/1995		No

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. 1	U.S. Patent Document	Name of Patentee or Applicant	Publication Date	Related	Copy Enclosed
		Number Kind Code ²				
	125	5,408,373	Bajorek et al.	4/18/1995		No
	126	5,410,259	Fujihara et al.	4/25/1995		No
	127	5,412,329 (Previously Submitted 11/25/02)	Iino et al.	5/2/1995		No
	128	5,412,987	Bergstrom et al.	5/9/1995		No
	129	5,416,429	McQuade et al.	5/16/1995		No
	130	5,422,516	Hosokawa et al.	6/6/1995		No
	131	5,422,574	Kister	6/6/1995		No
	132	5,430,614	Difrancesco	7/4/1995		No
	133	5,434,513	Fujii et al.	7/18/1995		No
	134	5,436,504	Chakravorty et al.	7/25/1995		No
	135	5,442,282	Rostoker et al.	8/15/1995		No
	136	5,449,903	Arney et al.	9/12/1995		No
	137	5,454,158	Fontana, Jr. et al.	10/3/1995		No
	138	5,454,904	Ghezzi et al.	10/3/1995		No
	139	5,455,390 (Previously Submitted 7/10/02)	DiStefano et al.	10/3/1995		No
	140	5,455,419	Bayer et al.	10/3/1995		No
	141	5,461,326	Woith et al.	10/24/1995		No
	142	5,463,233	Norling	10/31/1995		No
	143	5,465,009	Drabik et al.	11/7/1995		No
	144	5,467,067	Field et al.	11/14/1995		No
	145	5,467,068	Field et al.	11/14/1995		No
	146	5,471,148	Sinsheimer et al.	11/28/1995		No
	147	5,472,539	Saia et al.	12/5/1995		No
	148	5,475,280	Jones et al.	12/12/1995		No
	149	5,475,318 (Previously Submitted 7/10/02)	Marcus et al.	12/12/1995		No
	150	5,476,211 (Previously Submitted 7/10/02)	Khandros	12/19/1995		No
	151	5,485,304	Kaeriyama	1/16/1996		No
	152	5,489,552	Merchant et al.	2/6/1996		No
	153	5,490,034	Zavracky et al.	2/6/1996		No
	154	5,496,668	Guckel et al.	3/5/1996		No
	155	5,497,033	Fillion et al.	3/5/1996		No
	156	5,510,724	Itoyama et al.	4/23/1996		No
	157	5,513,430	Yanof et al.	5/7/1996		No
	158	5,516,418	Doss et al.	5/14/1996		No
	159	5,517,126	Yamaguchi	5/14/1996		No
	160	5,521,518 (Previously Submitted 7/10/02)	Higgins	5/28/1996		No
	161	5,521,522 (Previously Submitted 7/25/03)	Abe et al.	5/1996		No
	162	5,531,018	Saia et al.	7/12/1996		No
	163	5,531,022	Beaman et al.	7/2/1996		No
	164	5,532,613	Nagasawa et al.	7/2/1996		No
	165	5,534,205	Faley et al.	7/9/1996		No
	166	5,534,784 (Previously Submitted 7/10/02)	Lum et al.	7/9/1996		No

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. 1	U.S. Patent Document		Name of Patentee or Applicant	Publication Date	Related	Copy Enclosed
		Number	Kind Code ²				
	167	5,548,181		Jones	8/20/1996		No
	168	5,550,406		McCormick	8/27/1996		No
	169	5,552,925		Worley	9/3/1996		No
	170	5,557,514		Seare et al.	9/17/1996		No
	171	5,563,343		Shaw et al.	10/8/1996		No
	172	5,576,147		Guckel et al.	11/19/1996		No
	173	5,578,976		Yao	11/26/1996		No
	174	5,587,623		Jones	12/24/1996		No
	175	5,591,910		Lin	1/7/1997		No
	176	5,592,037		Sickafus	1/7/1997		No
	177	5,594,357		Nakajima	1/14/1997		No
	178	5,596,194		Kubena et al.	1/21/1997		No
	179	5,596,219		Hierold	1/21/1997		No
	180	5,605,844		Oki et al.	2/25/1997		No
	181	5,613,861		Smith et al.	3/25/1997		No
	182	5,619,097		Jones	4/8/1997		No
	183	5,623,213		Liu et al.	4/22/1997		No
	184	5,624,872		Liu et al.	4/29/1997		No
	185	5,629,918		Ho et al.	5/13/1997		No
	186	5,632,631 (Previously Submitted 7/10/02)		Fjelstad et al.	5/27/1997		No
	187	5,633,552		Lee et al.	5/27/1997		No
	188	5,635,846		Beaman et al.	6/3/1997		No
	189	5,642,056		Nakajima et al.	6/24/1997		No
	190	5,644,177		Guckel et al.	7/1/1997		No
	191	5,645,684		Keller	7/8/1997		No
	192	5,646,464		Sickafus	7/8/1997		No
	193	5,647,785		Jones et al.	7/15/1997		No
	194	5,652,559		Saia et al.	7/29/1997		No
	195	5,653,019		Bernhardt et al.	8/5/1997		No
	196	5,656,552		Hudak et al.	8/12/1997		No
	197	5,657,394		Schwartz et al.	8/12/1997		No
	198	5,658,698		Yagi et al.	8/19/1997		No
	199	5,660,680		Keller	8/26/1997		No
	200	5,665,253		Kubena et al.	9/9/1997		No
	201	5,683,594		Hocker et al.	11/4/1997		No
	202	5,692,951		Huff	12/2/1997		No
	203	5,693,426		Lee et al.	12/2/1997		No
	204	5,696,392		Char et al.	12/9/1997		No
	205	5,705,932		Fredrickson	1/6/1998		No
	206	5,710,466		Allen et al.	1/20/1998		No
	207	5,719,073		Shaw et al.	2/17/1998		No
	208	5,736,850		Legal	4/7/1998		No
	209	5,739,945		Tayebati	4/14/1998		No
	210	5,742,174		Kister et al.	4/21/1998		No
	211	5,758,537		Throssel	6/2/1998		No
	212	5,768,009		Little	6/6/1998		No

U.S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant	Publication Date	Related	Copy Enclosed
		Number	Kind Code ²				
	213	5,777,328		Gooch	7/7/1998		No
	214	5,777,329		Westphal et al.	7/7/1998		No
	215	5,783,905		Greschner et al.	7/21/1998		No
	216	5,789,753		Gooch et al.	8/4/1998		No
	217	5,801,057		Smart et al.	9/1/1998		No
	218	5,804,983		Nakajima et al.	9/8/1998		No
	219	5,805,375		Fan et al.	9/8/1998		No
	220	5,817,201		Greschner et al.	10/6/1998		No
	221	5,819,749		Lee et al.	10/13/1998		No
	222	5,829,126		Nagao et al.	11/3/1998		No
	223	5,830,372		Hierold	11/3/1998		No
	224	5,834,975		Bartlett et al.	11/10/1998		No
	225	5,841,137		Whitney	11/24/1998		No
	226	5,846,849		Shaw et al.	12/8/1998		No
	227	5,847,454		Shaw et al.	12/8/1998		No
	228	5,847,571		Liu et al.	12/8/1998		No
	229	5,848,685		Smith et al.	12/15/1998		No
	230	5,871,158		Frazier	2/6/1999		No
	231	5,872,459		Pasiecznik, Jr.	2/16/1999		No
	232	5,905,241		Park et al.	5/18/1999		No
	233	5,909,069		Allen et al.	6/1/1999		No
	234	5,909,280		Zavracky	6/1/1999		No
	235	5,969,591		Fung	10/19/1999		No
	236	6,650,460		Kurematsu	11/18/2003		No

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant	Publication Date	Copy Enclosed	T ³
		Office ³	Number ⁴	Kind Code ⁵				
	237	EP	0 102 069 A2		Nissan Motor Company, Limited	7-Mar-84	Yes	
	238	EP	0 331 282		Hewlett-Packard Company	6-Sep-89	Yes	
	239	EP	0 355 273 A1		Canon Kabushiki Kaisha	28-Feb-90	Yes	
	240	EP	0 365 151 A2		Hewlett-Packard Company	25-Apr-90	Yes	
	241	EP	0 404 799 B1		The Board of Trustees of the Leland Stanford Junior University	2-Jan-91	Yes	
	242	EP	0 413 042 A1		IBM Corporation	20-Feb-91	Yes	
	243	EP	0 453 716 A2		IBM Corporation	30-Oct-91	Yes	
	244	EP	0 453 716 A3		IBM Corporation	30-Oct-91	Yes	
	245	EP	0 480 645 B1		Canon Kabushiki Kaisha	15-Apr-97	Yes	
	246	EP	0 493 425 B1		British Telecommunications	8-Jul-92	Yes	
	247	EP	0 500 980 A1		Tencor Instruments	9-Feb-92	Yes	
	248	EP	0 544 305 A2		Nitto Denko	2-Jun-93	Yes	

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant	Publication Date	Copy Enclosed	T ⁵
		Office ³	Number ⁴	Kind Code ⁵				
	249	EP	0 544 305 A3		Corporation Nitto Denko Corporation	2-Jun-93	Yes	
	250	EP	0 665 590 B1		Canon Kabushiki Kaisha	2-Aug-95	Yes	
	251	EP	0 701 135 A1		Hughes Aircraft Company	13-Mar-96	Yes	
	252	EP	0 701 135 B1		Hughes Electronic Corporation	13-Mar-96	Yes	
	253	EP	0 707 310 A1		Hewlett-Packard Company	17-Apr-96	Yes	
	254	EP	0 711 029 B1		Canon Kabushiki Kaisha	8-May-96	Yes	
	255	EP	0 802 419 A2		NEC Corporation	22-Oct-97	Yes	
	256	EP	0 802 419 A3		NEC Corporation	12-Aug-98	Yes	
	257	FR	2639154		Christian et al.	18-May-90	Yes	
	258	JP	01-150862		Mitsubishi Electric Corp.	13-Jun-89	Yes	X
	259	JP	01-287484		Hitachi LTD	20-Nov-89	Yes	X
	260	JP	03-081669		Tokyo Kasoode Kenkyosho:KK	8-Apr-91	Yes	X
	261	JP	04-088649		Mitsubishi Electric Corp.	23-Mar-92	Yes	X
	262	JP	04-094147		Hitachi LTD	26-Mar-92	Yes	X
	263	JP	04-111331		Eito Kogyo:KK	13-Apr-92	Yes	X
	264	JP	04-360549		Nippon Denshi Zairo KK	14-Dec-92	Yes	X
	265	JP	04-361543		Mitsubishi Electric Corp	15-Dec-92	Yes	X
	266	JP	05-290907		Fujitsu Ltd.	5-Nov-93	Yes	X
	267	JP	06-027144		Silicon System Inc.	4-Feb-94	Yes	X
	268	JP	06-069294		Fuji Electric Co. Ltd.	11-Mar-94	Yes	X
	269	JP	06-151532		Tokyo Electron Yamanashi KK	31-May-94	Yes	X
	270	JP	06-204304		Okii Electric Ind Co Ltd	22-Jul-94	Yes	X
	271	JP	06-265577		Mitsubishi Electric Corp.	22-Sep-94	Yes	X
	272	JP	07-007052		Seiko-Epson Corp	10-Jan-95	Yes	X
	273	JP	58-162045		Telmecc Co. Ltd.	26-Sep-83	Yes	X
	274	JP	61-272946		NEC Corporation	3-Dec-86	Yes	X
	275	JP	63-151041		Mitsubishi Electric Corp.	23-Jun-88	Yes	X
	276	JP	63-293934		Hitachi	30-Nov-88	Yes	X
	277	KR	10-0013608 (Previously Submitted 5/25/04)		Tokyo Electron co.	6-Sep-90	Yes	
	278	WO	1988/007697		British Telecommunications Public Limited Company; STANELY, Ian, William SHEPHERD, John,	10-Jun-98	Yes	

FOREIGN PATENT DOCUMENTS								
Examiner Initials ¹	Cite No. ²	Foreign Patent Document			Name of Patentee or Applicant	Publication Date	Copy Enclosed	T ⁶
		Office ³	Number ⁴	Kind Code ⁵				
	279	WO	1989/007258		Nicholas The Board of Trustees of the Leland Stanford Junior University	10-Aug-98	Yes	
	280	WO	1990/000735		University of Hawaii	25-Jan-90	Yes	
	281	WO	1990/008397		The Board of Trustees of the Leland Stanford Junior University	26-Jul-90	Yes	
	282	WO	1990/015517		Labinal Components & Systems, Inc.	13-Dec-90	Yes	
	283	WO	1991/005284		British Telecommunications Public Limited Company	18-Apr-91	Yes	
	284	WO	1992/020842		Cornell Research Foundation, Inc.	16-Nov-92	Yes	
	285	WO	1993/018382		Kopin Corporation	16-Sep-93	Yes	
	286	WO	1994/012887		Micromodule Systems, Inc.	9-Jun-94	Yes	
	287	WO	1994/029671		DANISCH, Lee, A..	22-Dec-94	Yes	
	288	WO	1997/009584		IBM Corporation	13-Mar-97	Yes	
	289	WO	1998/026300		GGB Industries, Inc.	18-Jun-98	Yes	

OTHER PRIOR ART – NONPATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	Copy Enclosed	T ²
	290	"Probe Card Stiffener With Theta Adjust," IBM Technical Bulletin (2 pages) (no publication information)	Yes	
	291	"Ultra-Small Test Probe" (2 pages) (No publication information)	Yes	
	292	BARSOTTI C., et al. "Very High Density Probing," (Tektronix), 1988 International Test Conference, pp.608-614, (1988).	Yes	
	293	BEILEY Mark et al., "A Micromachined Array Probe Card-Characterization," IEEE Transactions on Components, Packaging, and manufacturing Tehcnology - Part B, Vol. 18, No.1, pp.184-191, February 1995.	Yes	
	294	BURNS F.C. et al., "Fixed Probe Test Adapter," Research Disclosure, No. 319, 90A064135, November 1990.	Yes	
	295	DA-YUAN Shih, "Elasticon-Integrated Probe Technology," (IBM), June 1995.	Yes	
	296	DIETRICH T.R. et al. "Photoetchable Glass for Microsystems: tips for atomic force microscopy", J. of Micromechanics and Microengineering, ISSN: 0960-1317, Vol. 3, No. 4, pp.187-189, December 1993.	Yes	
	297	GENIN D. et al., "Probing Considerations in C-4 Testing of IC Wafers," IBM, The International J. of Microcircuits and Electronic Packaging, (ISSN 1063-1674), Vol. 15, No. 4, pp 229-238, Fourth Quarter 1992.	Yes	

OTHER PRIOR ART – NONPATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	Copy Enclosed	T ²
	298	Hirano T. et al, "Silicon Microprobing Array for Testing and Burn-In," (IEEE), pp.89-94, July 1994.	Yes	
	299	KIEWITT D.A., "Microtool fabrication by etch pit replication," Rev. Sci. Instrum., Vol.44, No.12, pp.1741-1742, 1973.	Yes	
	300	LAIL P. et al., "Chapter 5 - Interconnections and Connectors", Handbook of Electronic Package Design, pp.239-255, 1991.	Yes	
	301	LESLIE B. et al. "Membrane Probe Card Technology," IEEE, (1988 International Test Conference), pp.601-607, 1988.	Yes	
	302	MACHIDA K., "Interconnect Technology of the 1990s", Surface Mount Technology, pp. 3-12.	Yes	
	303	MILOSEVIC I. et al., "Straight Wall Bumps for High Lead Count Devices: Photolithography and Physical Properties", Materials Research Society Symposium Proceedings, Vol. 154, pp.425-440, 1989.	Yes	
	304	OETINGER S. et al, "Needless Probe Card," Motorola Technical Developments Bulletin, Vol. 8, pp.45-46, October 1988.	Yes	
	305	STIX Gary, "Micron Machinations", published in Scientific American, pp.72-80, November 1992.	Yes	
	306	WASSINK R.J. Klein, "Soldering In Electronics, Chapter 12.2 – Good Soldered Joints", 2nd ed., pp.647-650, 1989.	Yes	
	307	YOUNKIN L., "Thin-Film-Hybrid Wafer-Probe Card Promises Speed and Density," Electronics Test, pp. 26-30, May 1989.	Yes	
	308	"Phicom Corporation's Amended Invalidity And Unenforceability Contentions," FormFactor, Inc. v. Phicom Corporation, United States District Court District of Oregon (Case No. 05-6062-HO)	Yes	
	309	"Defendants' Patent Local Rule 3-3 Preliminary Invalidity Contentions For U.S. Patent Nos. 6,246,247, 6,509,751, 6,624,648, And 7,073,254," FormFactor, Inc. v. Micronics Japan Co. and MJC Electronics Corp., United States District Court Northern District of California (Case No. 3:06-CV-07159 JSW)	Yes	

Examiner Signature	Date Considered
--------------------	-----------------

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Commonly owned US patent or application whose subject matter may be related to the subject matter of the instance patent application.